ON Semiconductor

FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #16797

Generic Copy

Issue Date: 25-Jul-2013

TITLE: Release of an additional tester platform (Micro Flex) for the C621-SOIC package (currently tested on TMT platform).

PROPOSED FIRST SHIP DATE: 25-Oct-2013 or earlier upon customer approval

AFFECTED CHANGE CATEGORY(S): Final test and QC insertions

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor Sales Office or your customer quality interface or Jean-Jacques Goubet <jean-jacques.goubet@onsemi.com>

NOTIFICATION TYPE:

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <quality@onsemi.com>.

DESCRIPTION AND PURPOSE:

This is to announce the release of Micro FLEX tester platform (An-UFlex) for Final Test and QC to improve tester capacity balancing and loading.

Qualification data:

QC ambient correlation data between the source tester (TMT) and the target tester (Micro FLEX – An-UFlex) is provided in a separate qualification report *(AMIS30621C6213(R)G_QCA_TMT-uFlex_Correlation_report)* attached in this Final PCN.

The correlation procedure that has been used is the same as in previous PCN's covering the release of additional tester platforms:

- 2 correlation units will be serialized and datalogged in 30 loops using the source tester platform where the device is already qualified. The test will be done at room temperature, using the QC program.
- Then, the same correlation units will be used to gather data on target tester microFLEX.
- The same datalogging procedure used for TMT will be followed for microFLEX.

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- Full parametric correlation will be performed and for every test the shift will be evaluated as follows:

□mean = abs(**mean(ref)-mean(qual))**
□sigma = 0 **if sigma(qual) < sigma(ref)**
□sigma = sigma(qual)**– sigma(ref)** **if sigma(qual) > sigma(ref)**

shift = □mean + 4 * □sigma

If shift < max(5% specwidth, 6*sigma(ref)) then correlation is OK for this test, else correlation is NOK for this test

- Any parameter that is NOK is independently analysed and explained.

ELECTRICAL CHARACTERISTIC SUMMARY:

Electrical Performance will continue to meet specifications.

List of affected Customer Specific Parts:

Internal ONSEMI sellable code	External ONSEMI part number
0C621-003-XTD/XTP	AMIS30621C6213G / AMIS30621C6213RG
0C621-005-XTD/XTP	AMIS30621AUA